



Die Attach Epoxy Characterization for Electronic Assemblies

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Die Attach Epoxy



Thunderbirds 2011

Sandia photographer Randy Montoya captured these photos of the US Air Force's Thunderbirds

**Great things are
done by a series of
small things
brought together**

Vincent Van Gogh

Outline



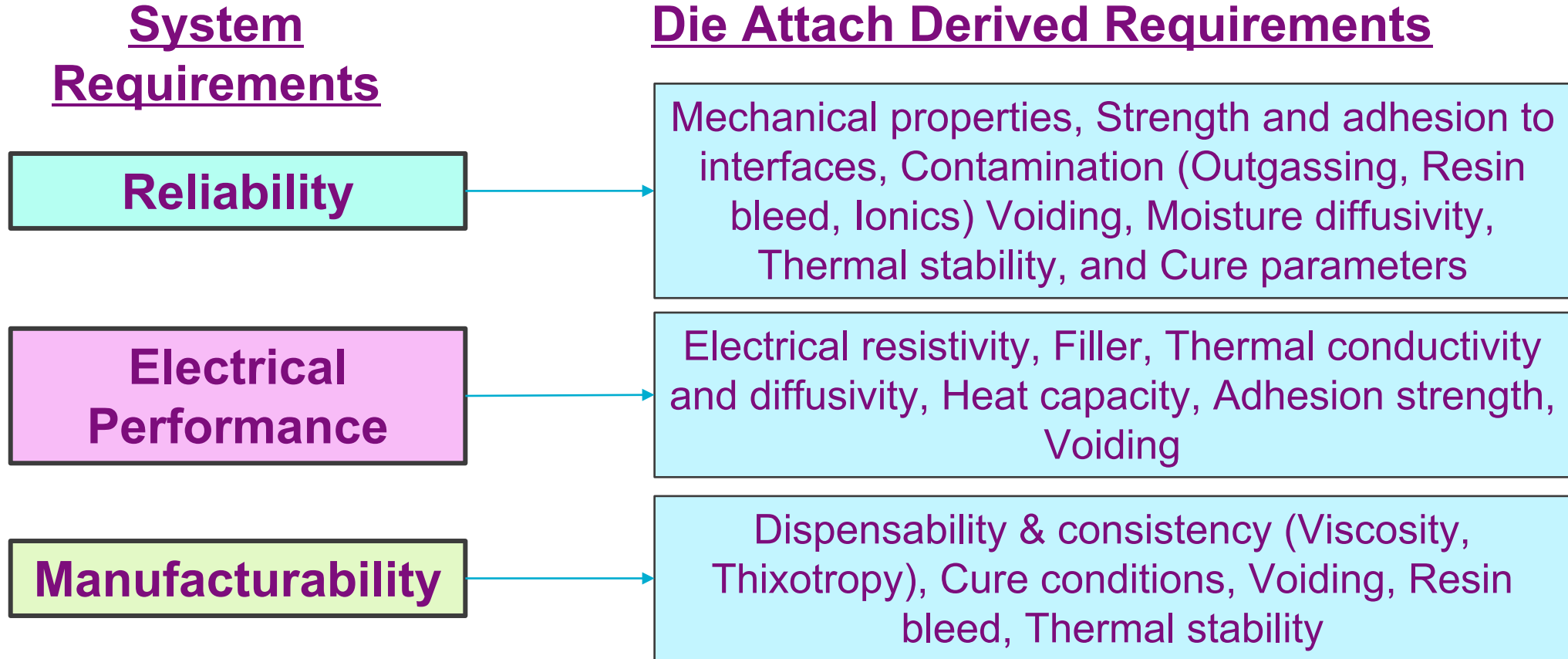
- Functionality of die attach
- System requirements drive die attach requirements
- Properties measurements
- Conclusions
- Acknowledgements
- Q & A

Die Attach Functionality



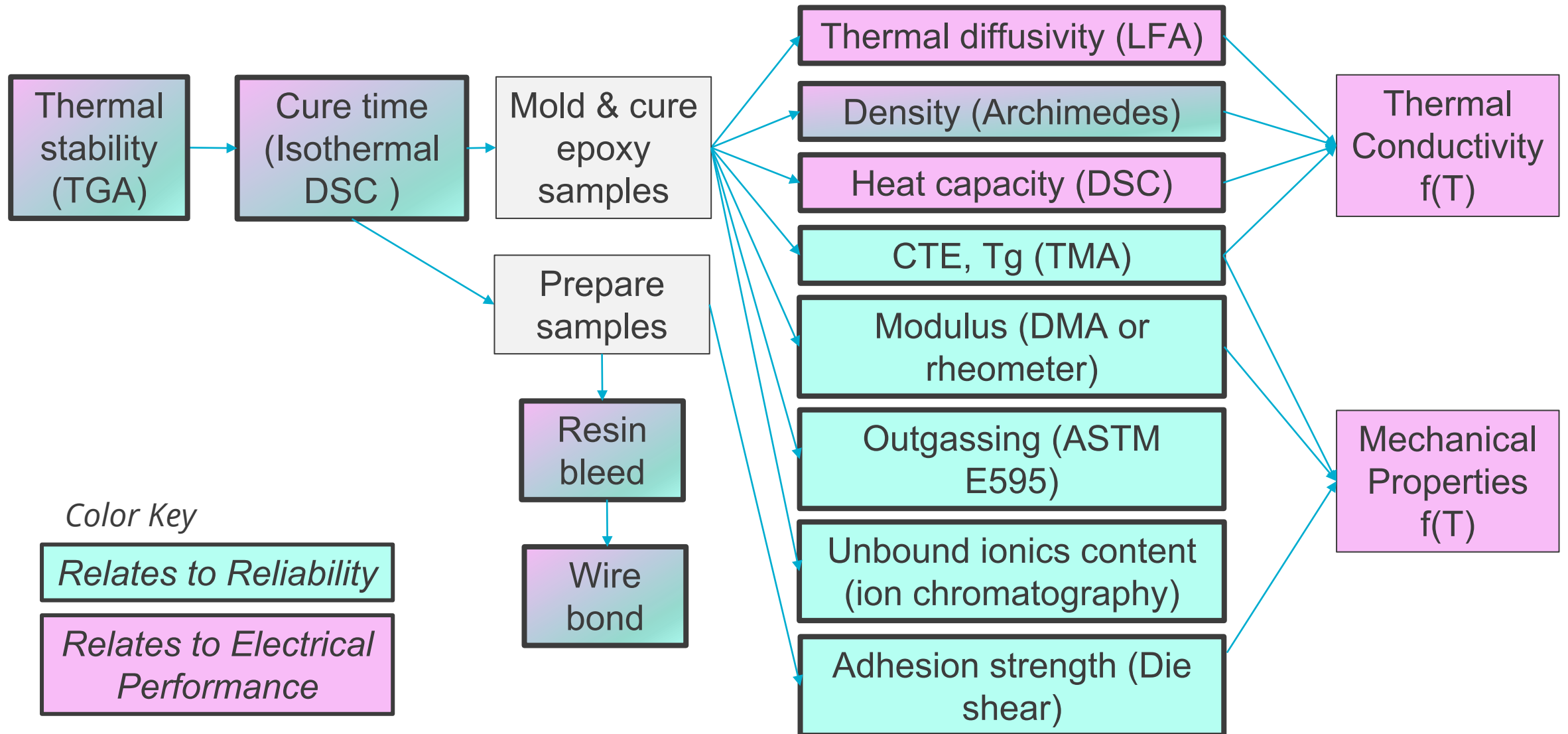
- Semiconductor chips are often attached to substrates, leadframes, ceramics or printed wiring boards with die attach adhesives
- This presentation will cover wire bonded products (no flip chip) and A stage vs B stage die attach materials
- Die attach adhesives are typically **polymer-based composites with non-polymer fillers**
- **Adheres** the silicon to either organic or metal surfaces (Solder mask, Cu, Au, etc.)
- **Accommodates thermal expansion mismatches** between silicon and substrate or leadframe
- Provides a **thermal path**
- Provides **electrical conductivity** per device needs
- Does so **without harming** or contaminating the circuit

System Requirements Drive Die Attach Requirements



*System and sub-system requirements are diverse –
no single material fits all needs*

Die Attach Materials Characterization

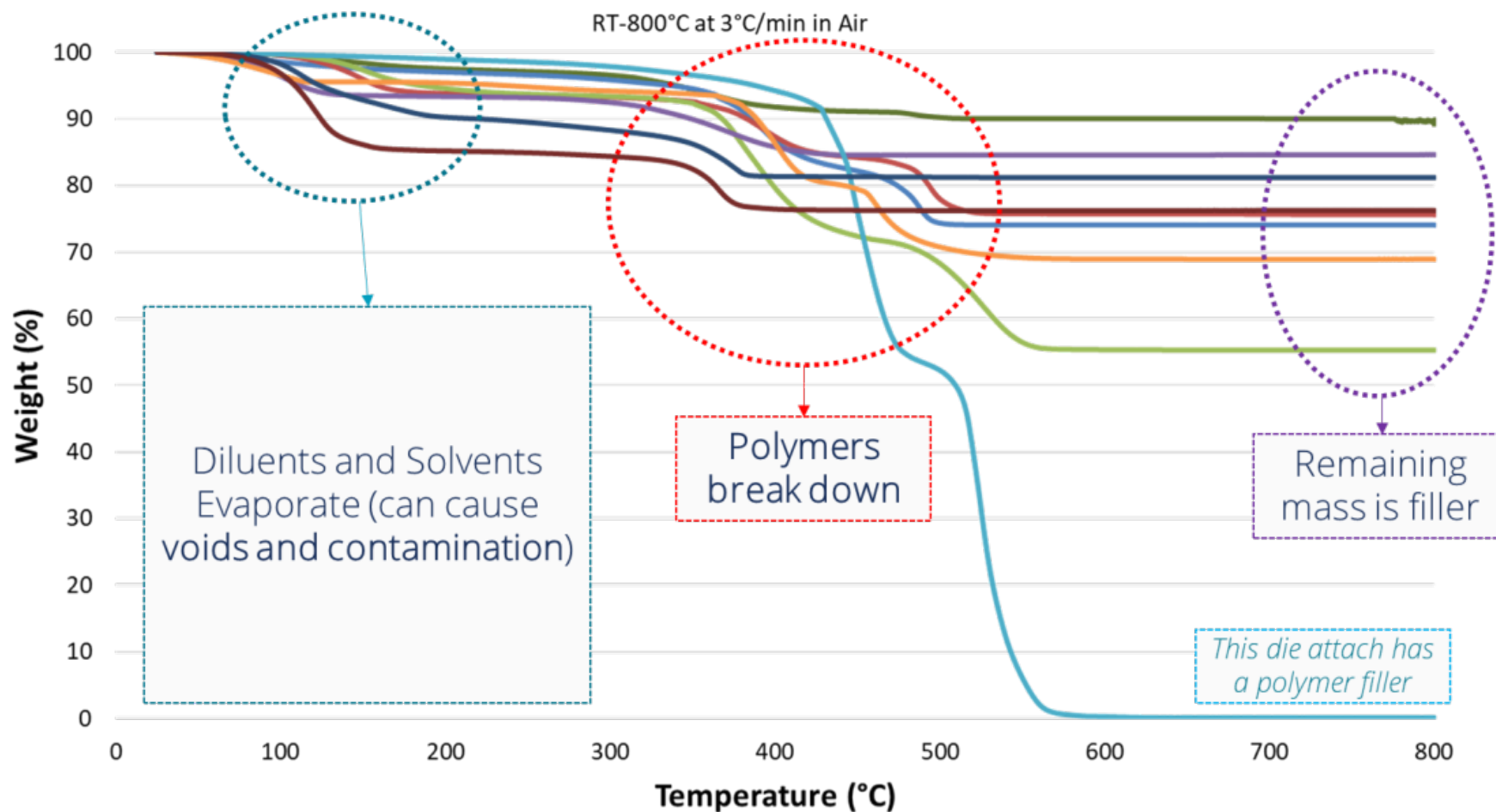


Thermal Stability



Measured by
thermal
gravimetric
analysis (TGA)

- TGA Q5000
- Heating rate of 3°C/min under air
- Jamie Kropka and Catherine Groves
- bleed

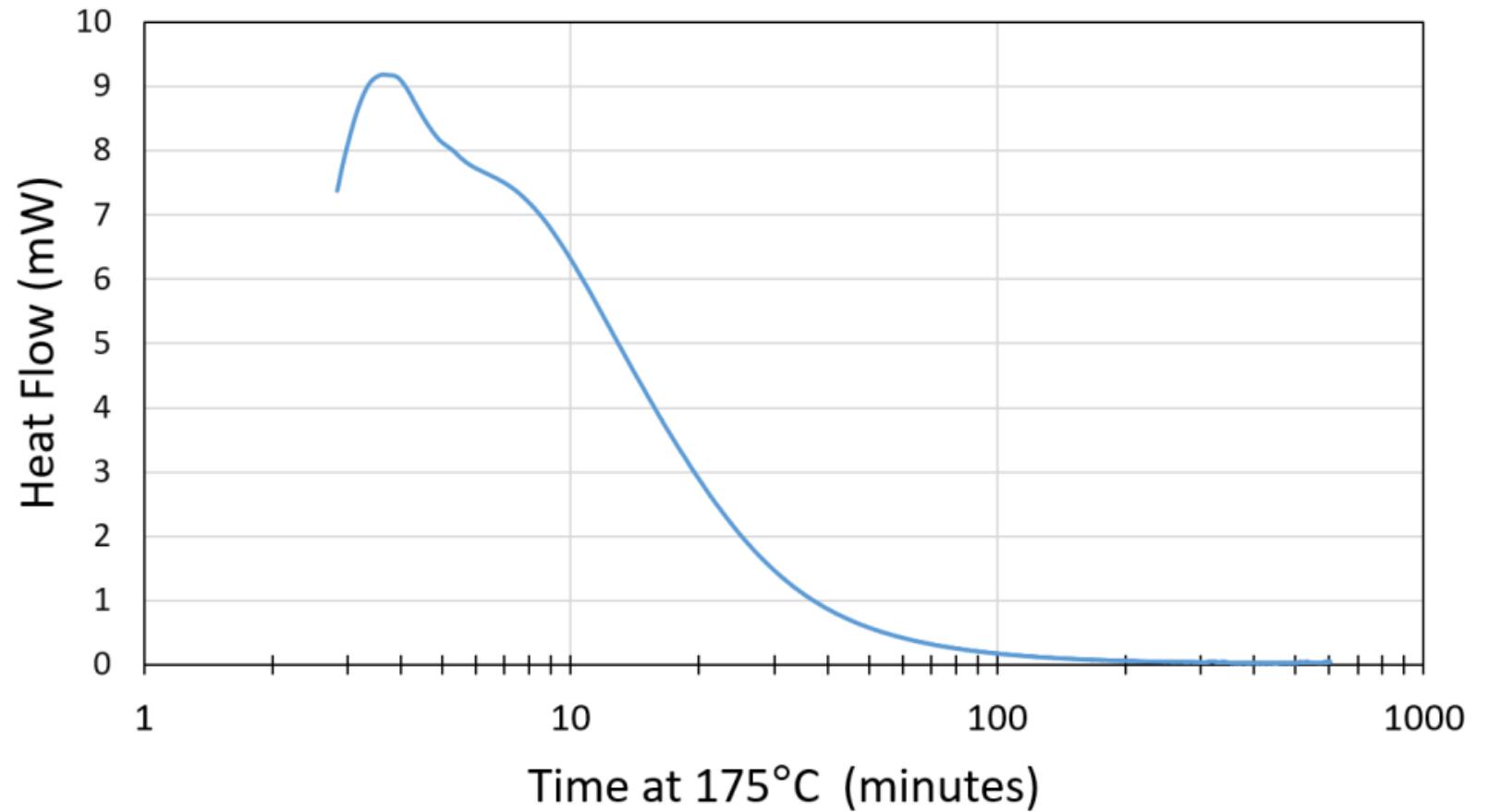


How do high temperatures affect die attach materials, possibly impacting device reliability and performance?

Cure Time at Temperature



- Isothermal hold at the supplier's recommended cure temperature
- Exotherm is evidence of chemical reaction
- Measured by Differential Scanning Calorimetry (DSC)

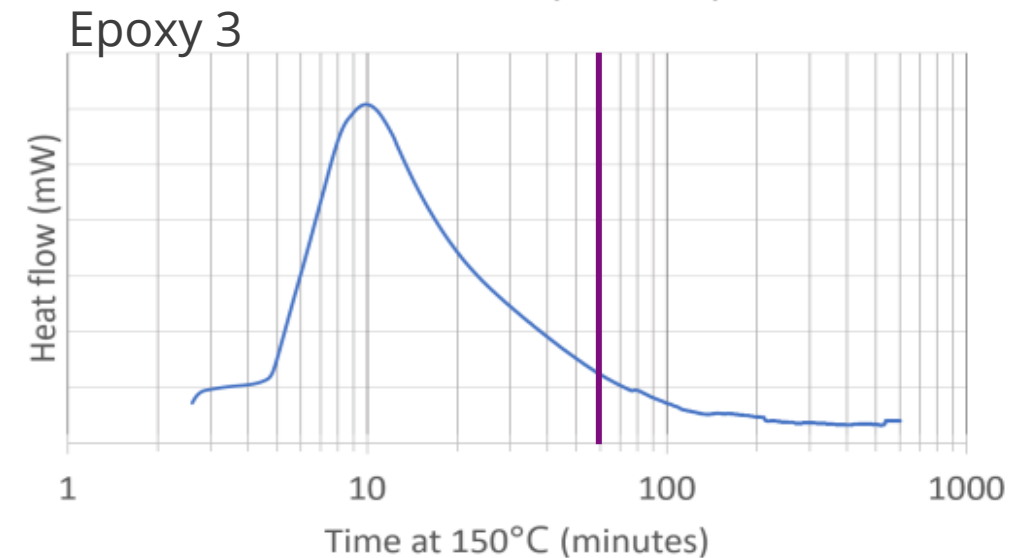
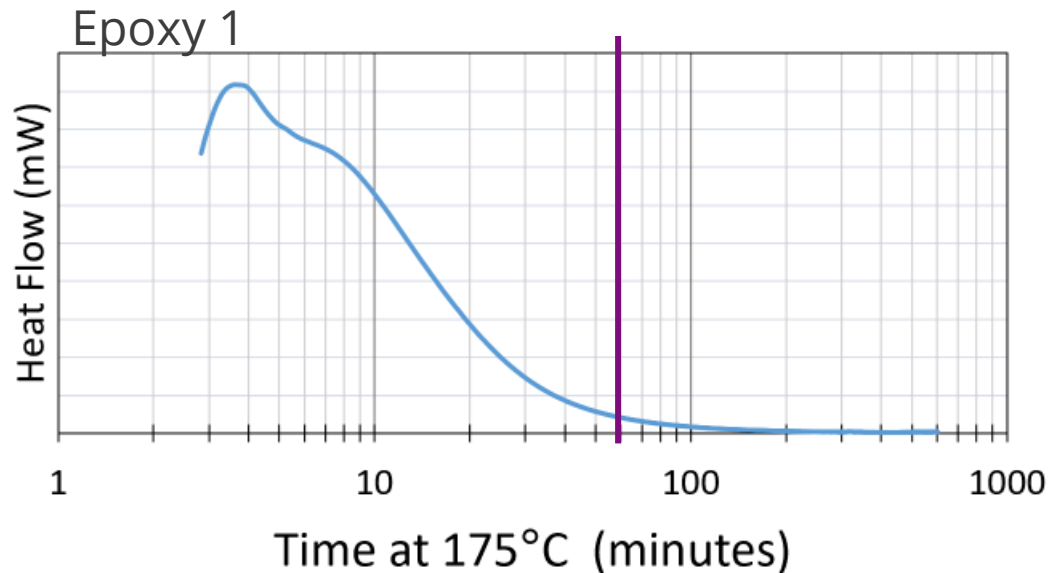
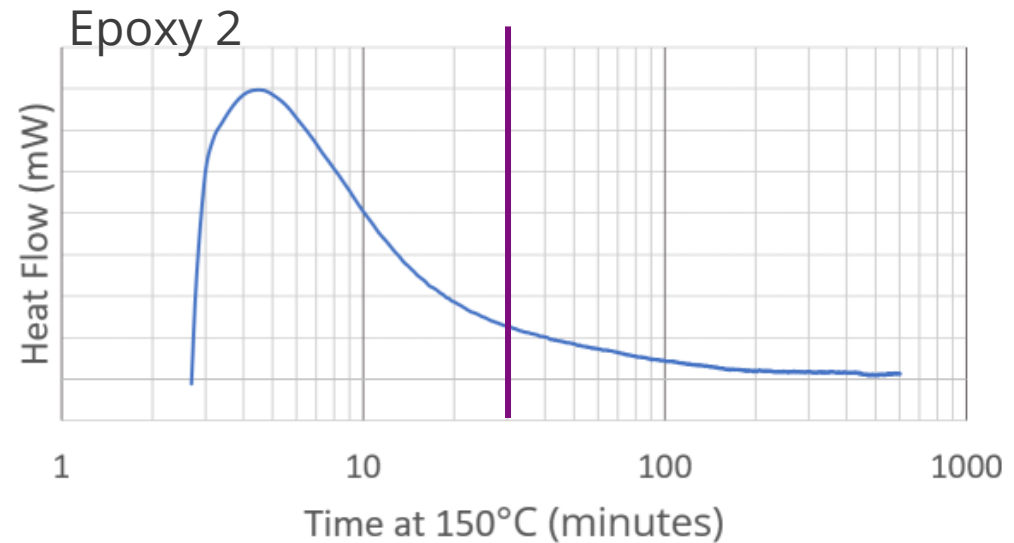


TA Instruments Q2000 series DSC
Jamie Kropka and Catherine Groves

Cure Time– Data Sheet vs Complete Cure



- Data sheet cure time recommendations often under-cure the epoxy
- Data sheet recommended cure times are shown with purple lines



Cure Conditions Can Affect Properties



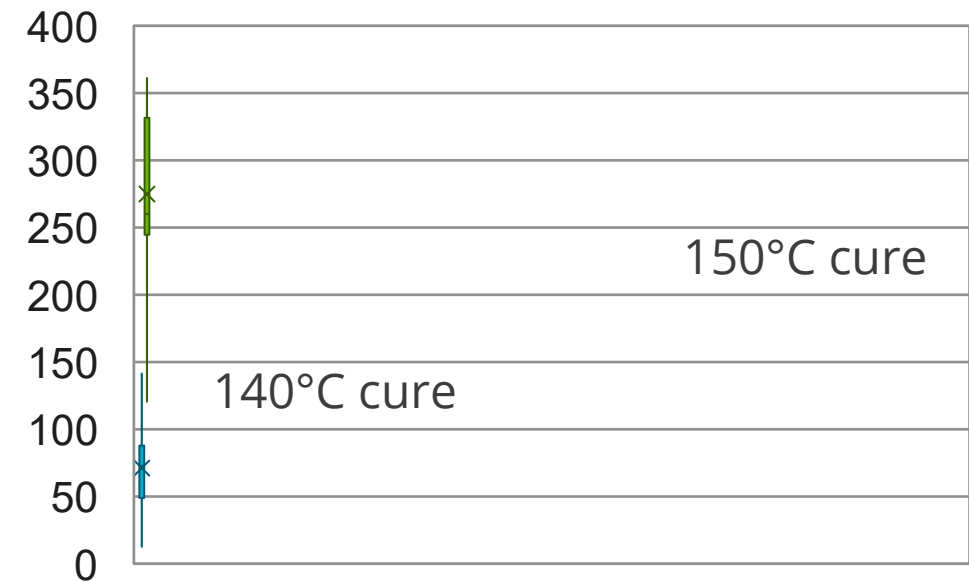
Outgassing performance can improve with higher cure temperature

Cure Temperature	Total Mass Loss (Outgassing ASTM E595)
60 C	1.18
71 C	0.91
80 C	0.8

Thermal conductivity of silver-filled die attach often will increase as cure temperature increases

Same epoxy – Different cure

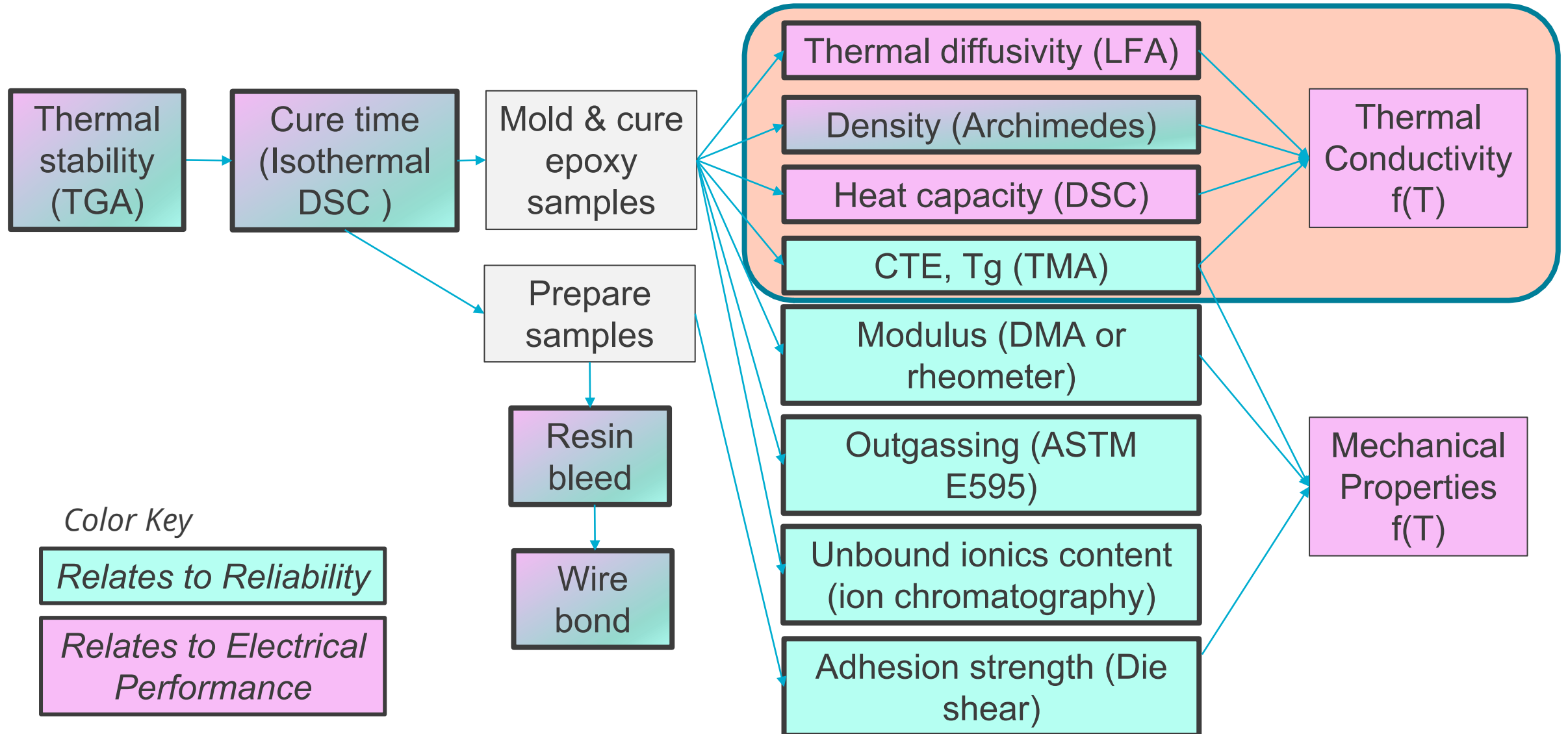
Die Attach Shear Strength



Connor Healey, Dage 4000 die shear tester

Die attach properties can depend on the cure process

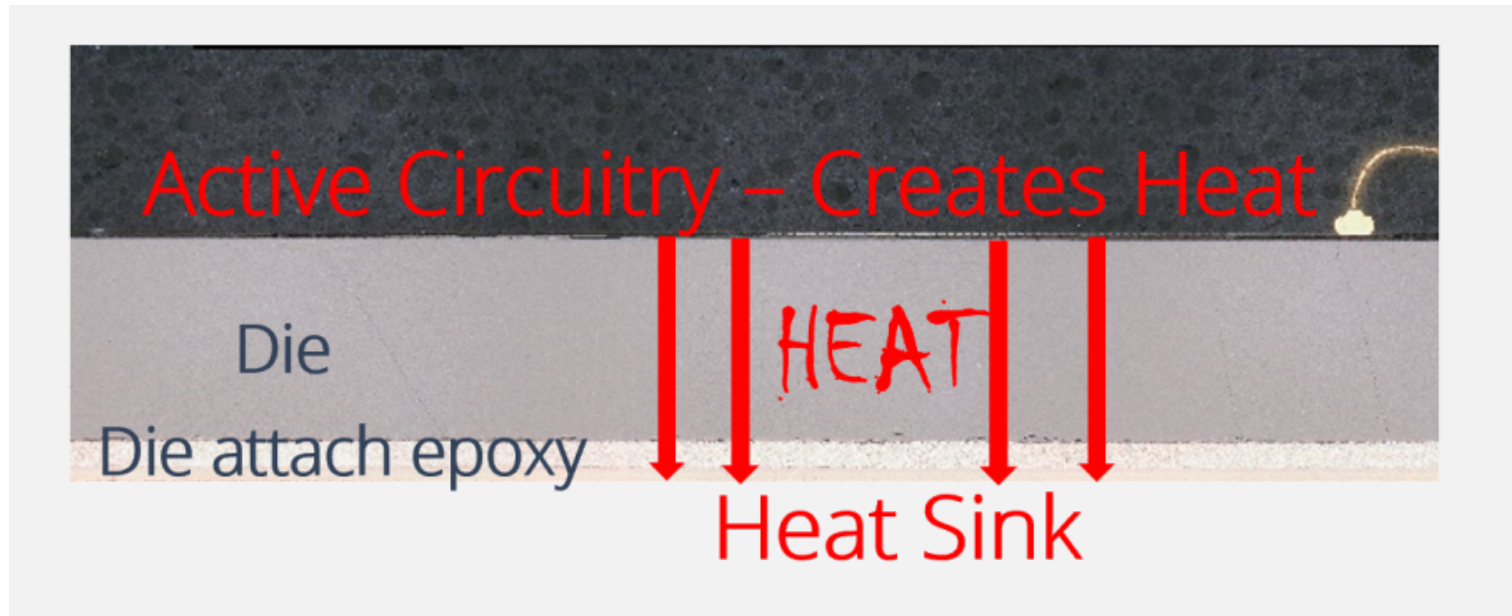
Die Attach Materials Characterization



Thermal Conductivity



- Heat generated by the active circuitry of the die can transfer through the die attach



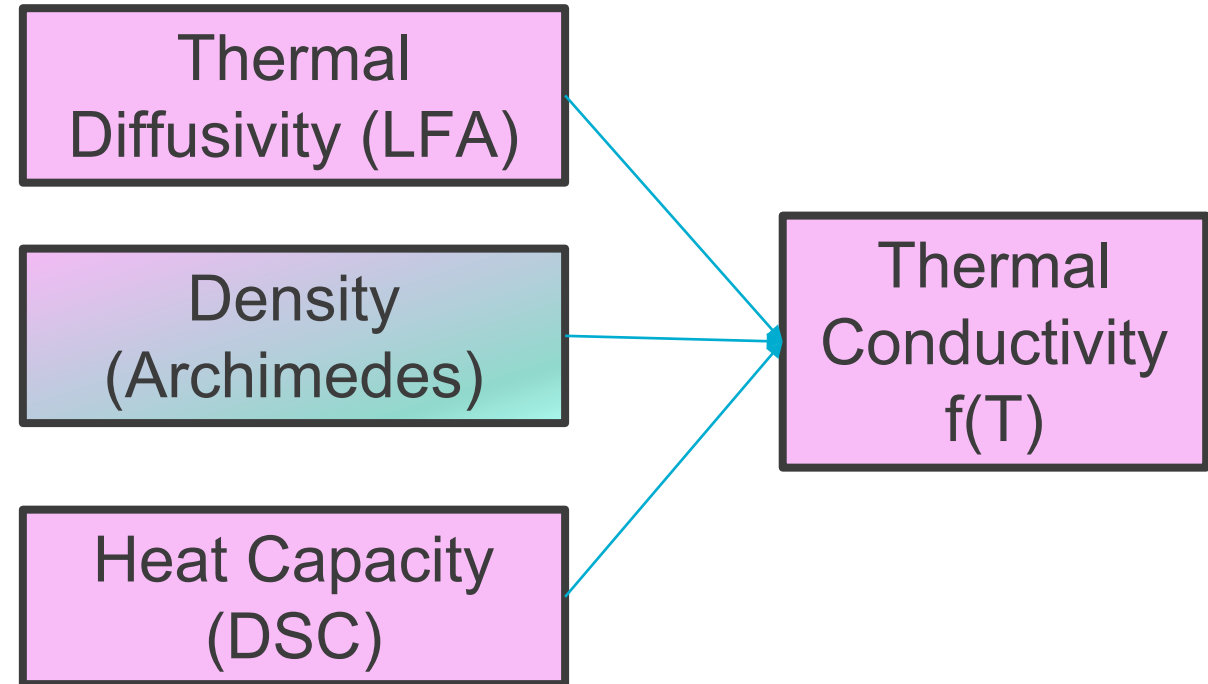
Thermally conductive die attach can remove excess heat and lowers junction temperatures

Thermal Conductivity Measurement



$$\lambda = \alpha C_p \rho$$

λ	Thermal conductivity
α	Thermal diffusivity
C_p	Specific Heat Capacity
ρ	Density



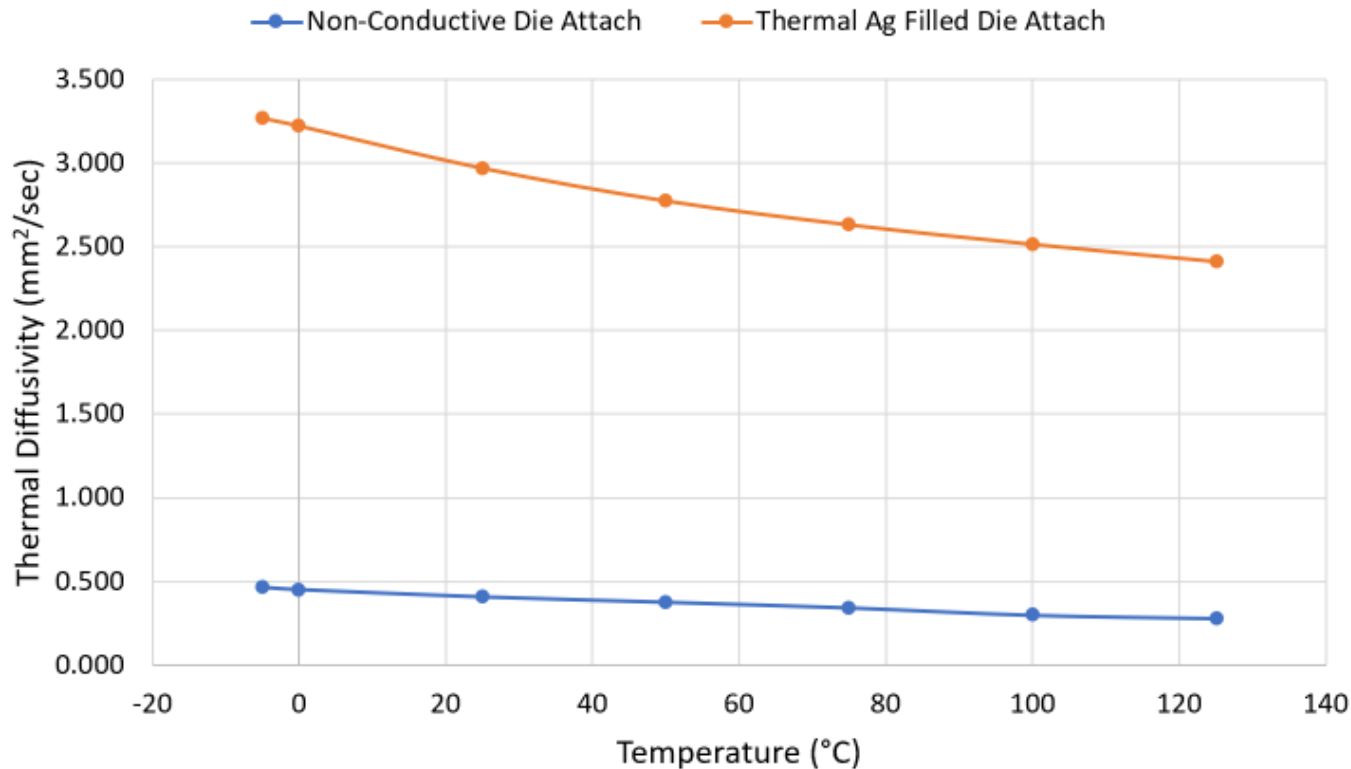
Thermal Diffusivity Measurement

$$\lambda = \alpha C_p \rho$$

α Thermal diffusivity



Designation: E1461 – 13 (Reapproved 2022)



Netzsch LFA 467 Hyperflash
Pin Yang and Mia Blea

Standard Test Method for Thermal Diffusivity by the Flash Method¹

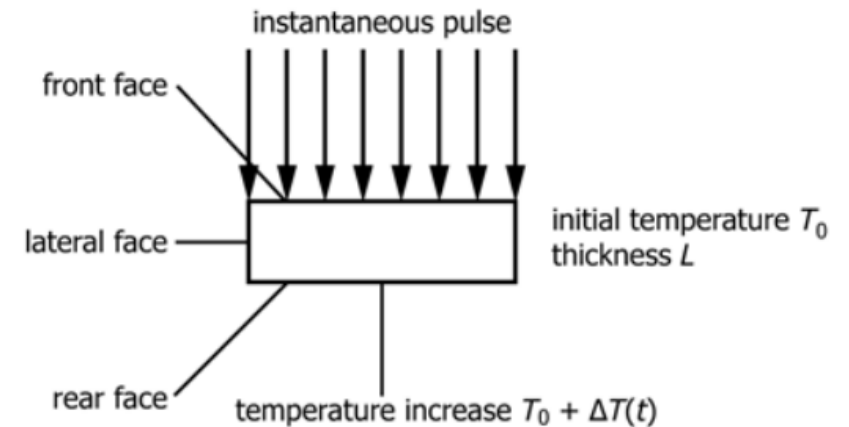


FIG. 2 Schematic of the Flash Method

Specific Heat Measurement



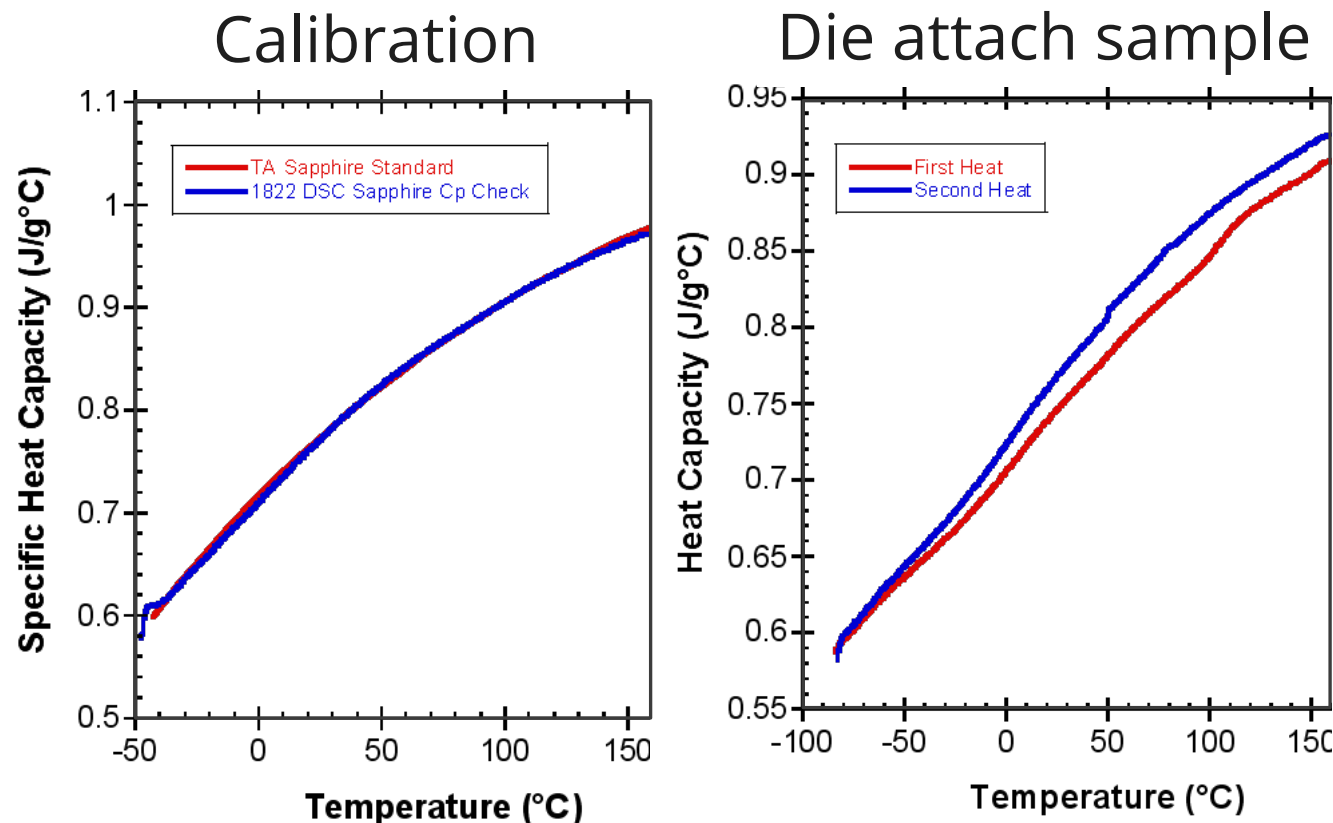
$$\lambda = \alpha C_p \rho$$

C_p Specific Heat Capacity



Designation: E1269 – 11 (Reapproved 2018)

**Standard Test Method for
Determining Specific Heat Capacity by Differential Scanning
Calorimetry¹**



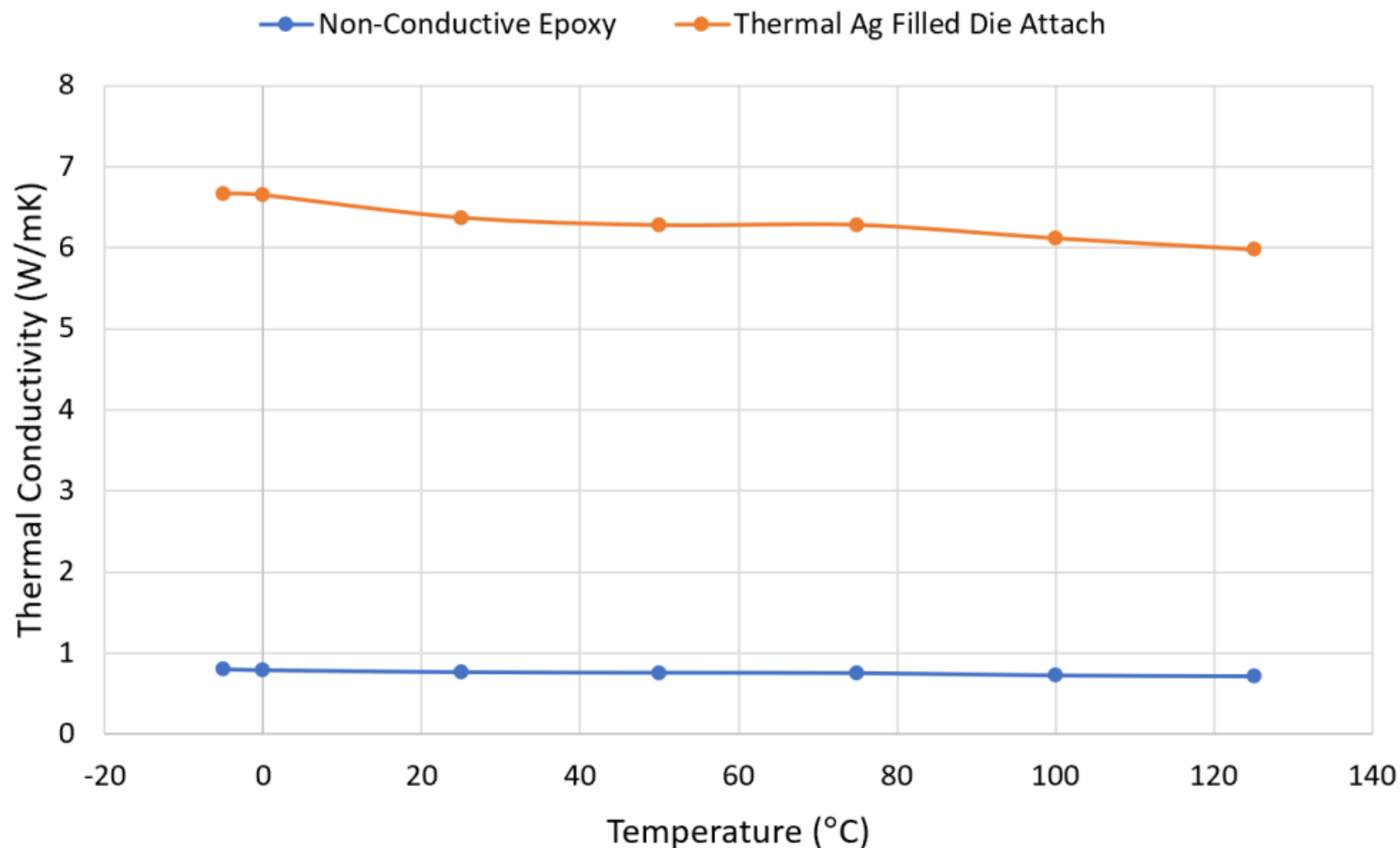
- TA Instruments Q2000 series DSC
- Performed with nitrogen sealed hermetic pans
- Jamie Kropka and Catherine Groves

Thermal Conductivity

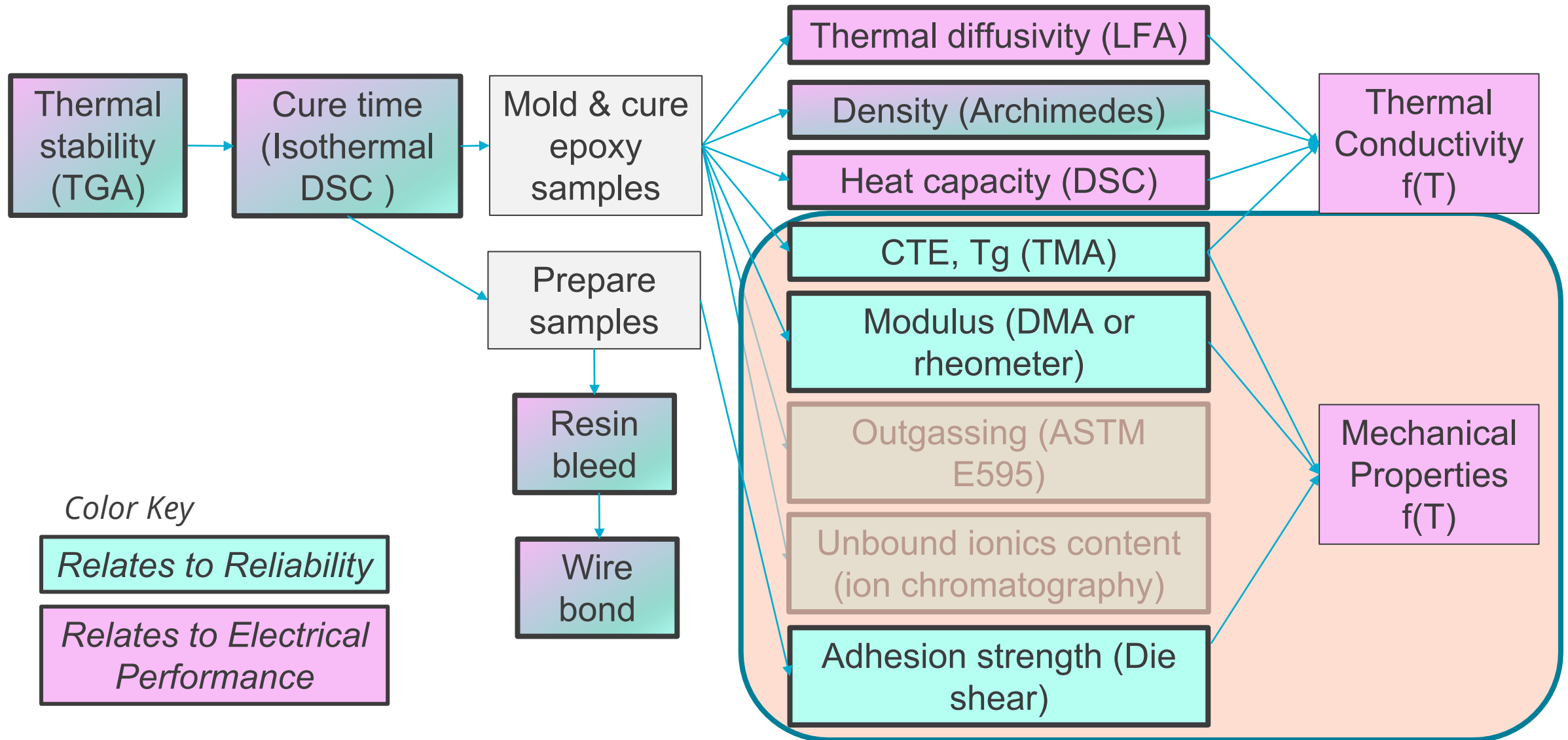


$$\lambda = \alpha C_p \rho$$

λ Thermal conductivity



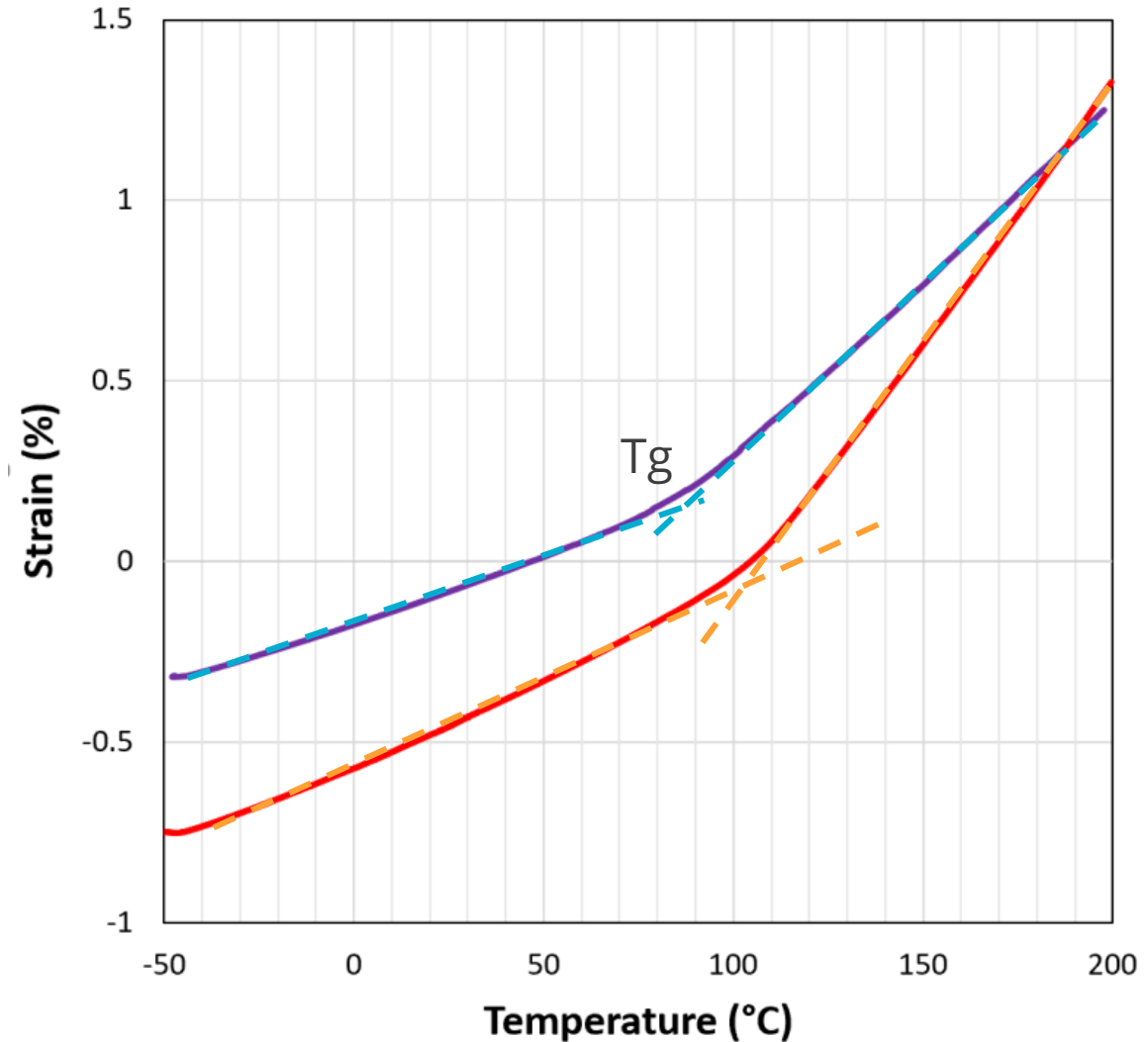
Die Attach Materials Characterization



Mechanical Properties – Coefficient of Thermal Expansion

Thermal Mechanical Analysis (TMA)

- Measures the sample during heating and cooling
- Thermal expansion coefficient (slope)
- Glass transition temperature (T_g) (inflection point)
- Shrinkage due to additional thermal excursions after cure

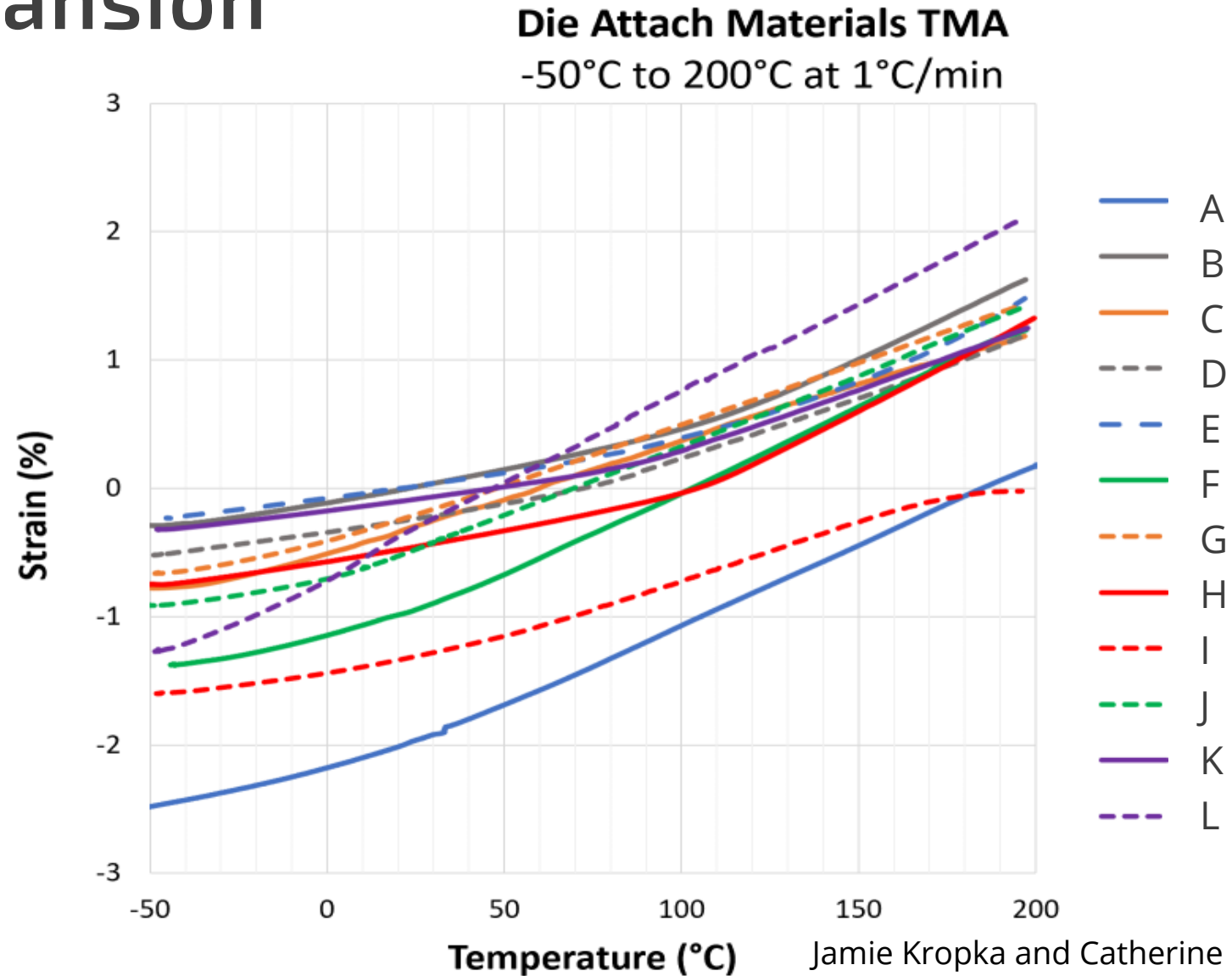


Jamie Kropka and Catherine Groves
Heating rate of 1°C/min in nitrogen

Mechanical Properties – Coefficient of Thermal Expansion



- Generally, lower thermal expansion is better for reliability
- Thermal expansion coefficient is part of the stress picture, but not all of it

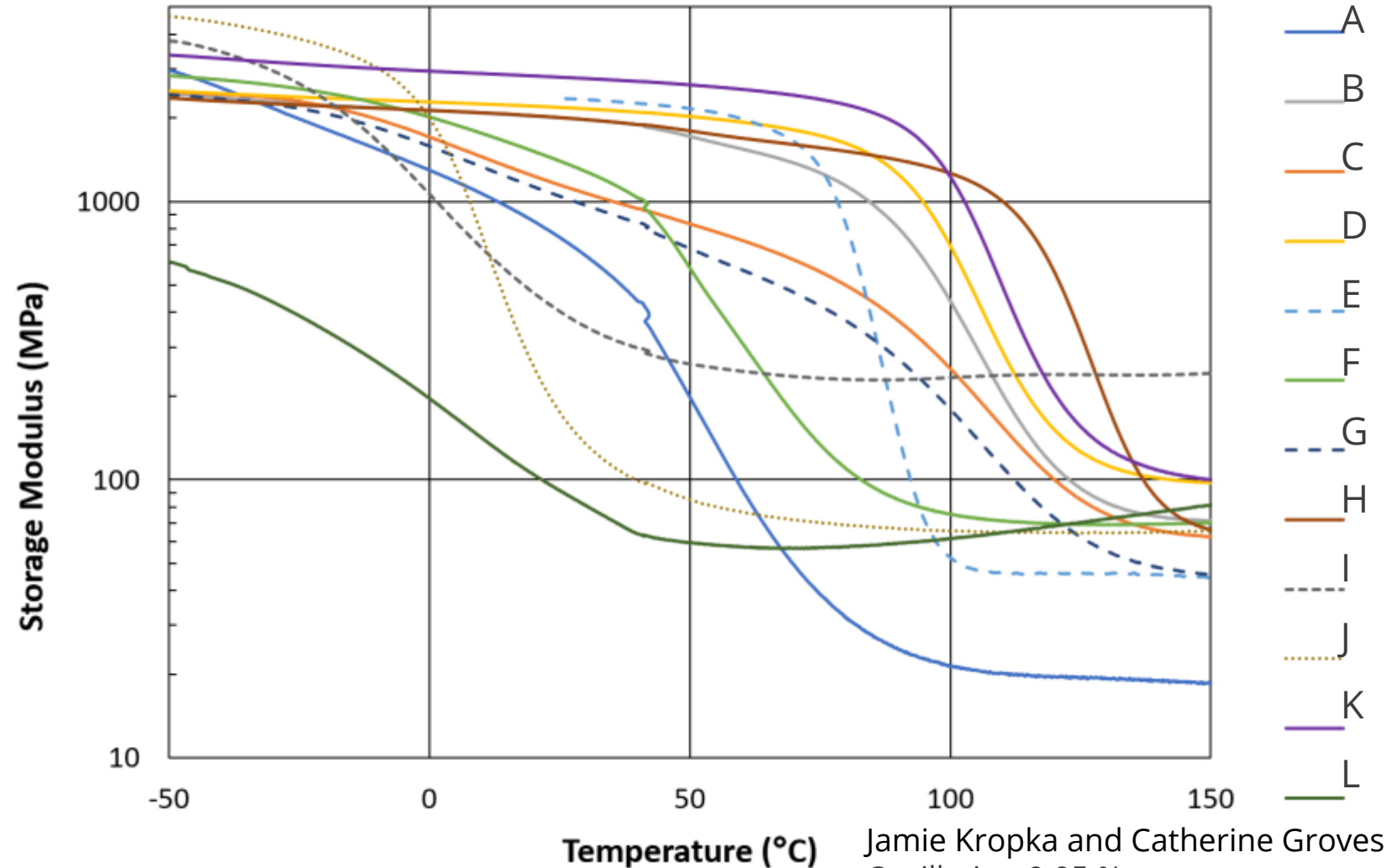


Jamie Kropka and Catherine Groves
Heating rate of 1°C/min in nitrogen

Mechanical Properties – Modulus

Equipment:

- ARES G2 torsional rheometer
- This technique measures shear storage modulus, not Young's modulus
- High modulus materials are stiff
- Low modulus materials are more flexible



Conclusions



Die attach material selections depend on the requirements of the system

- Material selections can affect reliability, manufacturability, and device functionality
- Characterization of critical properties improves predictive modelling fidelity versus data sheet values

To enable informed epoxy selection

- Start with the system requirements
- Derive material requirements from system requirements
- Use properties data that are trusted
- Understand that cure profile affects the die attach properties, and that data sheets often understate cure times

Thank You!!



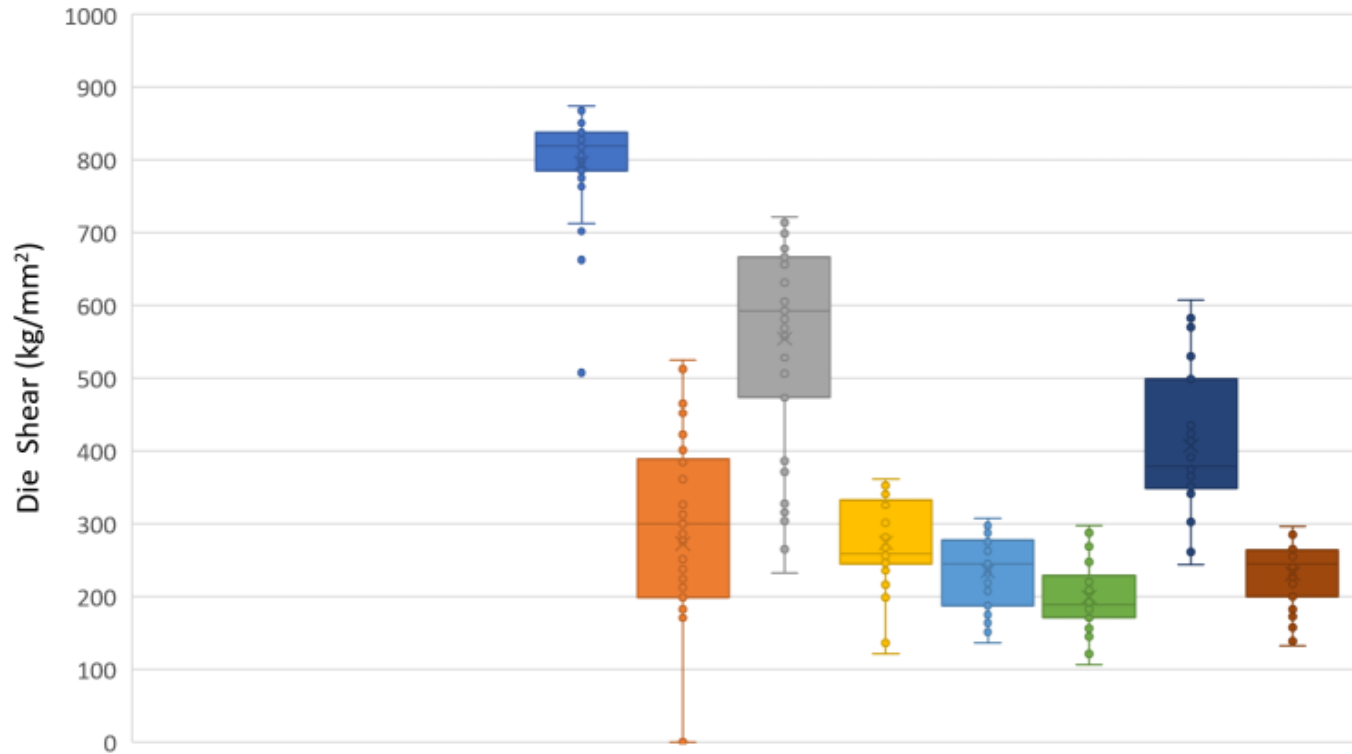
- We couldn't have done this work without you!
 - Mia Blea
 - Don Bradley
 - Shianne Carroll
 - Adrian Casias
 - Catherine Groves
 - Alvin Ha
 - Randy Hamm
 - Connor Healey
 - Jason James
 - Jamie Kropka
 - Erica McCready
 - Nalini Melon
 - Jason Tillotson
 - Daren Whitlock
 - Pin Yang

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Backup Slides



Die Shear Testing



Dage 4000, Connor Healey

Adhesion to different surfaces, cure schedule, cleanliness, and many other things affect die shear strength